TOSHIBA HIGH EFFICIENCY DIODE STACK (HED) SILICON EPITAXIAL TYPE

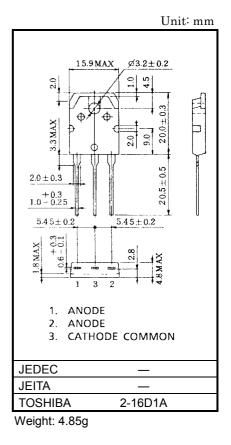
20DL2C41A,20FL2C41A,20GL2C41A

SWITCHING MODE POWER SUPPLY APPLICATIONS CONVERTER & CHOPPER APPLICATION

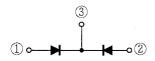
- Repetitive Peak Reverse Voltage $: V_{RRM} = 200, 300, 400V$
- Average Output Rectified Current : IO = 20A
- Ultra Fast Reverse-Recovery Time $: t_{rr} = 35ns$ (Max)
- Low Switching Losses and Output Noise

MAXIMUM RATINGS (Ta = 25°C)

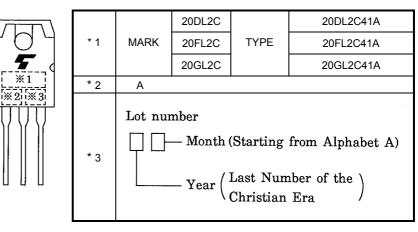
CHARACTERISTIC		SYMBOL	RATING	UNIT	
Repetitive Peak Reverse Voltage	20DL2CZ41A		200	V	
	20FL2CZ41A	V _{RRM}	300		
	20GL2CZ41A		400		
Average Output Rectified Current		Ι _Ο	20	А	
Peak One Cycle Surge Forward Current (Non Repetitive)		I _{FSM}	100 (50H _Z)	A	
			110 (60H _Z)		
Junction Temperature		Tj	-40~150	°C	
Storage Temperature Range		T _{stg}	-40~150	°C	
Screw Torque		-	0.8	N∙m	



POLARITY



MARKING



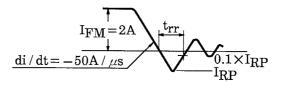
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	TYP.	MAX	UNIT
Peak Forward Voltage (Note 1)	20DL2C41A		I _{FM} = 10A	_	0.98	
	20FL2C41A	V_{FM}			1.3	V
	20GL2C41A				1.8	
Repetitive Peak Reverse Current (Note 1)		I _{RRM}	V _{RRM} = Rated		50	μA
Reverse Recovery Time (Note 1)		t _{rr}	I _F = 2.0A, di / dt = - 50A / μs	_	35	ns
Forward Recovery Time (Note 1)		t _{fr}	I _F = 1A	_	100	ns
Thermal Resistance		R _{th (j−c)}	DC Total, Junction to Case	_	1.5	°C/W

Note 1: A value of one cell.

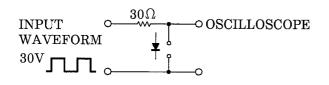
Note 2: trr TEST CIRCUIT

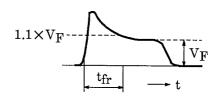
Note 3: tfr TEST CIRCUIT



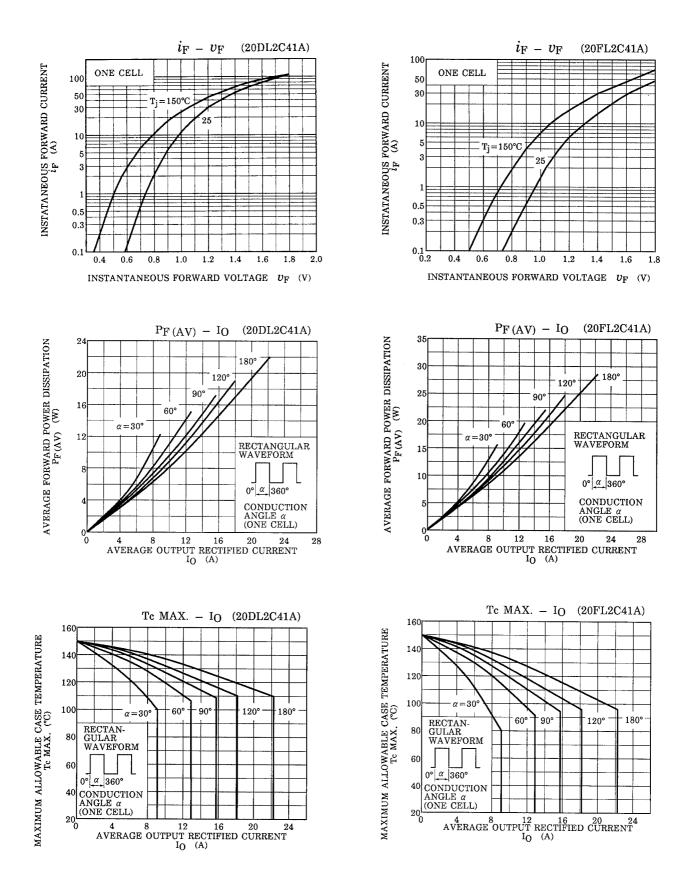
trr WAVEFORM

t_{fr} Waveform





TOSHIBA



TOSHIBA

1000

 $T_j = 25^{\circ}C$

30 50

(TYPICAL)

f = 1.0 MHz

 $Ta = 25^{\circ}C$

50

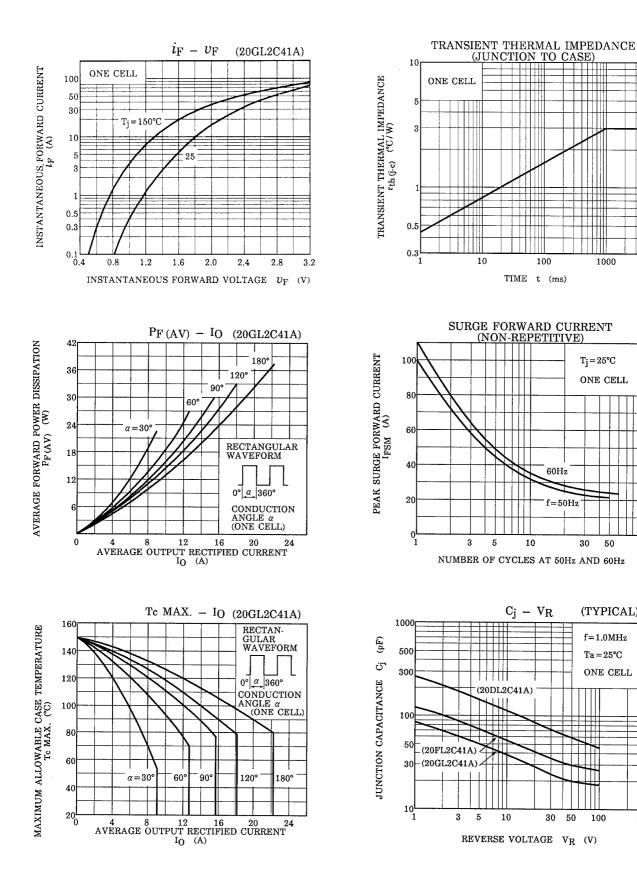
100

300

ONE CELL

100

ONE CELL



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